

# MOTOR BRIDGE CONTROLLER

# 1 FEATURES

- OPERATING SUPPLY VOLTAGE 8V TO 28V, OVERVOLTAGE MAX. 40V
- OPERATING SUPPLY VOLTAGE 6V WITH IMPLEMENTED STEPUP CONVERTER
- QUIESCENT CURRENT IN STANDBY MODE LESS THAN 50µA
- ISO 9141 COMPATIBLE INTERFACE
- CHARGE PUMP FOR DRIVING A POWER MOS AS REVERSE BATTERY PROTECTION
- PWM OPERATION FREQUENCY UP TO 30KHZ
- PROGRAMMABLE CROSS CONDUCTION PROTECTION TIME
- OVERVOLTAGE, UNDERVOLTAGE, SHORT CIRCUIT AND THERMAL PROTECTION
- REAL TIME DIAGNOSTIC

#### Figure 2. Block Diagram

#### Figure 1. Package

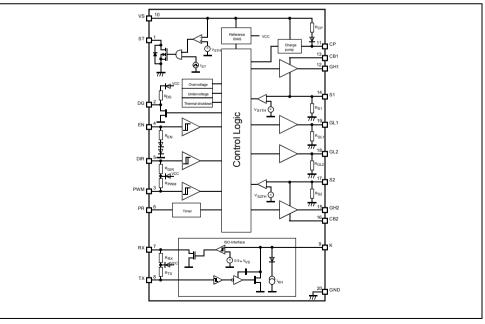


# Table 1. Order Codes

Part Number	Package
L9904	SO20
L9904TR	Tape & Reel

#### 2 DESCRIPTION

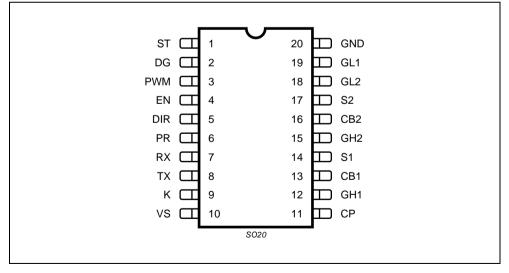
Control circuit for power MOS bridge driver in automotive applications with ISO 9141bus interface.



# Table 2. Pin Function

N°	Pin	Description	
1	ST	Open Drain Switch for Stepup converter	
2	DG	Open drain diagnostic output	
3	PWM	PWM input for H-bridge control	
4	EN	Enable input	
5	DIR	Direction select input for H-bridge control	
6	PR	Programmable cross conduction protection time	
7	RX	ISO 9141 interface, receiver output	
8	TX	ISO 9141 interface, transmitter input	
9	К	ISO 9141 Interface, bidirectional communication K-line	
10	VS	Supply voltage	
11	CP	Charge pump for driving a power MOS as reverse battery protection	
12	GH1	Gate driver for power MOS highside switch in halfbridge 1	
13	CB1	External bootstrap capacitor	
14	S1	Source/drain of halfbridge 1	
15	GH2	Gate driver for power MOS highside switch in halfbridge 2	
16	CB2	CB2 External bootstrap capacitor	
17	S2	Source/drain of halfbridge 2	
18	GL2	Gate driver for power MOS lowside switch in halfbridge 2	
19	GL1	Gate driver for power MOS lowside switch in halfbridge 1	
20	GND	Ground	

# Figure 3. Pin Connection (Top view)



Symbol	Parameter	Value	Unit	
V <sub>CB1</sub> , V <sub>CB2</sub>	Bootstrap voltage	-0.3 to 40	V	
$I_{CB1}$ , $I_{CB2}$	Bootstrap current	-100	mA	
V <sub>CP</sub>	Charge pump voltage	-0.3 to 40	V	
I <sub>CP</sub>	Charge pump current	-1	mA	
V <sub>DIR</sub> ,V <sub>EN</sub> ,V <sub>PWM</sub> ,V <sub>TX</sub>	Logic input voltage	-0.3 to 7	V	
I <sub>DIR</sub> ,I <sub>EN</sub> ,I <sub>PWM</sub> ,I <sub>TX</sub>	Logic input current	±1	mA	
$V_{DG}$ , $V_{RX}$	Logic output voltage	-0.3 to 7	V	
I <sub>DG</sub> ,I <sub>RX</sub>	Logic output current	-1	mA	
V <sub>GH1</sub> , V <sub>GH2</sub>	Gate driver voltage	-0.3 to V <sub>SX</sub> + 10	V	
I <sub>GH1</sub> , I <sub>GH2</sub>	Gate driver current	-1	mA	
V <sub>GL1</sub> , V <sub>GL2</sub>	Gate driver voltage	-0.3 to 10	V	
$I_{GL1}$ , $I_{GL2}$	Gate driver current	-10	mA	
Vĸ	K-line voltage	-20 to V <sub>S</sub>	V	
V <sub>PR</sub>	Programming input voltage	-0.3 to 7	V	
I <sub>PR</sub>	Programming input current	-1	mA	
$V_{S1}$ , $V_{S2}$	Source/drain voltage	-2 to V <sub>VS</sub> + 2	V	
I <sub>S1</sub> , I <sub>S2</sub>	Source/drain current	-10	mA	
V <sub>ST</sub>	Output voltage	-0.3 to 40	V	
I <sub>ST</sub>	Step up output current	-1	mA	
V <sub>VSDC</sub>	DC supply voltage	-0.3 to 28	V	
V <sub>VSP</sub>	Pulse supply voltage (T < 500ms)	40	V	
Ivs	DC supply current	-100	mA	

#### **Table 3. Absolute Maximum Ratings**

For externally applied voltages or currents exceeding these limits damage of the device may occur!

All pins of the IC are protected against ESD. The verification is performed according to MIL883C, human body model with R=1.5k $\Omega$ , C=100pF and discharge voltage ±2kV, corresponding to a maximum discharge energy of 0.2mJ.

# Table 4. Thermal Data

Symbol	Parameter	Value	Unit
TJ	Operating junction temperature	-40 to 150	°C
T <sub>JSD</sub>	Junction temperature thermal shutdown threshold	min 150	°C
T <sub>JSDH</sub>	Junction thermal shutdown hysteresis	typ 15	°C
R <sub>th j-amb</sub>	Thermal resistance junction to ambient <sup>1)</sup>	85	°C/W

1. see application note 110 for SO packages.

# **Table 5. Electrical Characteristcs**

(8V < V<sub>VS</sub> < 20V, V<sub>EN</sub> = HIGH, -40°C  $\leq$  T<sub>J</sub>  $\leq$  150°C, unless otherwise specified. The voltages are refered to GND and currents are assumed positive, when current flows into the pin

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
Supply (V	/S)					
V <sub>VS OVH</sub>	Overvoltage disable HIGH threshold		28	33	36	V
$V_{VSOVh}$	Overvoltage threshold hysteresis <sup>2)</sup>			1.6		V
V <sub>VS UVH</sub>	Undervoltage disable HIGH threshold		6		7	V
$V_{VS \ UVh}$	Undervoltage threshold hysteresis <sup>2)</sup>			0.66		V
I <sub>VSL</sub>	Supply current	V <sub>EN</sub> = 0 ; V <sub>VS</sub> = 13.5V; T <sub>J</sub> < 85°C			50	μA
I <sub>VSH</sub>	Supply current, pwm-mode	V <sub>VS</sub> = 13.5V; V <sub>EN</sub> = HIGH; V <sub>DIR</sub> = LOW; S1 = S2 = GND		8.1	13	mA
		$f_{PWM}$ = 20kHz; $C_{CBX}$ = 0.1µF; $C_{GLX}$ = 4.7nF; $C_{GHX}$ = 4.7nF;				
		$R_{PR}$ = 10k $\Omega$ ; $C_{PR}$ = 150pF				
I <sub>VSD</sub>	Supply current, dc-mode	V <sub>VS</sub> = 13.5V; V <sub>EN</sub> = HIGH; V <sub>DIR</sub> = LOW; S1 = S2 = GND		5.8	10	mA
		V <sub>PWM</sub> = LOW; C <sub>GHX</sub> = 4.7nF R <sub>PR</sub> = 10kΩ; C <sub>PR</sub> = 150pF				
Enable in	put (EN)				1	
V <sub>ENL</sub>	Low level				1.5	V
V <sub>ENH</sub>	High level		3.5			V
V <sub>ENh</sub>	Hysteresis threshold 2)			1		V
R <sub>EN</sub>	Input pull down resistance	V <sub>EN</sub> = 5V	16	50	100	kΩ
H-bridge	control inputs (DIR, PWM)					
V <sub>DIRL</sub> V <sub>PWML</sub>	Input low level				1.5	V
V <sub>DIRH</sub> V <sub>PWMH</sub>	Input high level		3.5			V
V <sub>DIRh</sub> V <sub>PWMh</sub>	Input threshold hysteresis 2)			1		V
R <sub>DIR</sub> R <sub>PWM</sub>	Internal pull up resistance to internal VCC <sup>3)</sup>	V <sub>DIR</sub> = 0; V <sub>PWM</sub> = 0	16	50	100	kΩ
DIAGNOS	STIC output (DG)					
V <sub>DG</sub>	Output drop	I <sub>DG</sub> = 1mA			0.6	V
$R_{DG}$	Internal pull up resistance to internal VCC <sup>3)</sup>	V <sub>DG</sub> = 0V	10	20	40	kΩ
Program	mable cross conduction protectio	n <sup>4)</sup>				
N <sub>PR</sub>	Threshold voltage ratio V <sub>PRH</sub> / V <sub>PRL</sub>	R <sub>PR</sub> = 10kΩ	1.8	2	2.2	
I <sub>PR</sub>	Current capability	V <sub>PR</sub> = 2V	-0.5			mA
ISO inter	face, transmission input (TX)	1	1	1	1	
V <sub>TXL</sub>	Input low level				1.5	V

# Table 5. Electrical Characteristcs (continued)

(8V < V<sub>VS</sub> < 20V, V<sub>EN</sub> = HIGH, -40°C  $\leq$  T<sub>J</sub>  $\leq$  150°C, unless otherwise specified. The voltages are refered to GND and currents are assumed positive, when current flows into the pin

It high level It hysteresis voltage 2) It hysteresis voltage 2) It hysteresis voltage 2) It out voltage high stage It high delay time It low delay time It low level It high level It hysteresis voltage 2) It current	$V_{TX} = 0$ $TX = HIGH; I_{RX} = 0; V_K = V_{VS}$ $TX = HIGH; V_{RX} = 0V$ $TX = LOW; I_{RX} = 1mA$ Fig. 1 $V_{TX} = HIGH$	3.5 10 4.5 5 -20V -20V 0.55 · Vvs	1 20 10 40 0.5 0.5 0.025 <sup>.</sup> Vvs	40 5.5 20 90 0.45 Vvs Vvs Vvs 0.8V	V V kΩ V kΩ Ω μs μs
rnal pull up resistance to rnal VCC 3)  receiver output (RX)  put voltage high stage  rnal pull up resistance ternal VCC <sup>3</sup> )  resistance to ground  put high delay time  K-line (K)  It low level  It high level  It hysteresis voltage 2)	TX = HIGH; $I_{RX}$ = 0; $V_K$ = $V_{VS}$ TX = HIGH; $V_{RX}$ = 0V TX = LOW; $I_{RX}$ = 1mA Fig. 1	4.5 5 -20V 0.55 · Vvs	20 10 40 0.5 0.5	5.5 20 90 0.45 Vvs Vvs	kΩ V kΩ Ω μs
mal VCC 3) receiver output (RX) out voltage high stage rnal pull up resistance ternal VCC <sup>3)</sup> resistance to ground out high delay time out low delay time <b>K-line (K)</b> It low level It high level It hysteresis voltage 2)	TX = HIGH; $I_{RX}$ = 0; $V_K$ = $V_{VS}$ TX = HIGH; $V_{RX}$ = 0V TX = LOW; $I_{RX}$ = 1mA Fig. 1	4.5 5 -20V 0.55 · Vvs	10 40 0.5 0.5	5.5 20 90 0.45 Vvs Vvs	V kΩ Ω μs
but voltage high stage         rmal pull up resistance         ternal VCC <sup>3</sup> )         resistance to ground         but high delay time         but low delay time         K-line (K)         tt low level         tt high level         tt hysteresis voltage 2)	TX = HIGH; V <sub>RX</sub> = 0V TX = LOW; I <sub>RX</sub> = 1mA Fig. 1	-20V -20V 0.55 · Vvs	40 0.5 0.5 0.025	20 90 0.45 · Vvs Vvs	kΩ Ω μs
rnal pull up resistance ternal VCC <sup>3)</sup> resistance to ground out high delay time out low delay time <b>K-line (K)</b> It low level It high level It hysteresis voltage 2)	TX = HIGH; V <sub>RX</sub> = 0V TX = LOW; I <sub>RX</sub> = 1mA Fig. 1	-20V -20V 0.55 · Vvs	40 0.5 0.5 0.025	20 90 0.45 · Vvs Vvs	kΩ Ω μs
ternal VCC <sup>3)</sup> resistance to ground but high delay time but low delay time <b>K-line (K)</b> It low level It high level It hysteresis voltage 2)	V <sub>RX</sub> = 0V TX = LOW; I <sub>RX</sub> = 1mA Fig. 1	-20V 0.55 · V <sub>VS</sub>	40 0.5 0.5 0.025	90 0.45 · Vvs Vvs	Ω μs
but high delay time but low delay time K-line (K) It low level It high level It hysteresis voltage 2)	I <sub>RX</sub> = 1mA Fig. 1	0.55 · V <sub>VS</sub>	0.5 0.5	0.45 · Vvs Vvs	μs
but low delay time K-line (K) It low level It high level It hysteresis voltage 2)		0.55 · V <sub>VS</sub>	0.5	V <sub>VS</sub> V <sub>VS</sub>	
K-line (K) it low level it high level it hysteresis voltage 2)	V <sub>TX</sub> = HIGH	0.55 · V <sub>VS</sub>	0.025.	V <sub>VS</sub> V <sub>VS</sub>	μS
it low level It high level It hysteresis voltage 2)	V <sub>TX</sub> = HIGH	0.55 · V <sub>VS</sub>		V <sub>VS</sub> V <sub>VS</sub>	
t high level t hysteresis voltage 2)	V <sub>TX</sub> = HIGH	0.55 · V <sub>VS</sub>		V <sub>VS</sub> V <sub>VS</sub>	
t hysteresis voltage 2)	V <sub>TX</sub> = HIGH	V <sub>VS</sub>			
	V <sub>TX</sub> = HIGH			0.8V	
it current	V <sub>TX</sub> = HIGH	-			
		-5		25	μA
resistance to ground	V <sub>TX</sub> = LOW; I <sub>K</sub> =10mA		10	30	Ω
rt circuit current	V <sub>TX</sub> = LOW	40		130	mA
smission frequency		60	100		kHz
I V <sub>VCC</sub> is 4.5V 5.5V	esign and verified in characterization				
time	$V_{VS}$ = 13.5V; Fig. 1 External loads at K-line: $R_{K}$ = 510 $\Omega$ pull up to $V_{VS}$ $C_{K}$ = 2.2nF to GND		2	6	μS
time			2	6	μS
ch high delay time	1		4	17	μS
ch low delay time	1		4	17	μS
rt circuit detection time	$V_{VS}$ = 13.5V; TX = LOW V <sub>K</sub> > 0.55 · V <sub>VS</sub>	10		40	μS
	•		•		
rge pump voltage	$V_{VS} = 8V$	V <sub>VS</sub> + 7V		V <sub>VS</sub> + 14V	
		V <sub>VS</sub> + 10V		V <sub>VS</sub> + 14V V <sub>VS</sub>	
	ch high delay time ch low delay time rt circuit detection time	to $V_{VS}$ $C_K = 2.2nF$ to GND time ch high delay time ch low delay time t circuit detection time $V_{VS} = 13.5V;$ TX = LOW $V_K > 0.55 \cdot V_{VS}$ rge pump voltage $V_{VS} = 8V$ $V_{VS} = 13.5V$	to Vvs $C_K = 2.2nF$ to GNDtime ch high delay time ch low delay timeImage: Chronic of the text of the text of the text of tex of text of tex of tex of text of text of text of	to Vvs $C_K = 2.2nF$ to GND     2       time     4       ch high delay time     4       ch low delay time     4       ch low delay time     4       th circuit detection time     Vvs = 13.5V; TX = LOW VK > 0.55 · Vvs     10       rge pump voltage     Vvs = 8V Vvs = 13.5V     Vvs + 7V Vvs +	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

## Table 5. Electrical Characteristcs (continued)

(8V < V<sub>VS</sub> < 20V, V<sub>EN</sub> = HIGH, -40°C  $\leq$  T<sub>J</sub>  $\leq$  150°C, unless otherwise specified. The voltages are refered to GND and currents are assumed positive, when current flows into the pin

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
I <sub>CP</sub>	Charging current V <sub>CP</sub> = V <sub>VS</sub> + 8V	V <sub>VS</sub> = 13.5V	-50	-75		μA
tCP	Charging time <sup>2)</sup> V <sub>CP</sub> = V <sub>VS</sub> + 8V			1.2	4	ms
f <sub>CP</sub>	Charge pump frequency	V <sub>VS</sub> = 13.5V	250	500	750	kHz
Drivers f	or external highside power MOS	·	•			
V <sub>CB1</sub> V <sub>CB2</sub>	Bootstrap voltage		7.5 10 10		14 14 14	V V V
R <sub>GH1L</sub> R <sub>GH2L</sub>	ON-resistance of SINK stage	$V_{CBX}$ = 8V; $V_{SX}$ = 0 $I_{GHX}$ = 50mA; $T_J$ = 25°C			10	Ω
		$V_{CBX}$ = 8V; $V_{SX}$ = 0 $I_{GHX}$ = 50mA; $T_J$ = 125°C			20	Ω
R <sub>GH1H</sub> R <sub>GH2H</sub>	ON-resistance of SOURCE stage	I <sub>GHX</sub> = -50mA; T <sub>J</sub> = 25°C I <sub>GHX</sub> = -50mA; T <sub>J</sub> = 125°C			10 20	Ω Ω
V <sub>GH1H</sub> V <sub>GH2H</sub>	Gate ON voltage (SOURCE)	$\label{eq:VVS} \begin{array}{l} V_{VS} = V_{SX} = 8V; \ I_{GHX} = 0; \\ C_{CBX} = 0.1\muF \end{array}$	V <sub>VS</sub> +6.5V		V <sub>VS</sub> +14V	
		$V_{VS}$ = $V_{SX}$ = 13.5V; $I_{GHX}$ = 0; $C_{CBX}$ = 0.1 $\mu$ F	V <sub>VS</sub> + 10V		V <sub>VS</sub> +14V	
		$V_{VS}$ = $V_{SX}$ = 20V; $I_{GHX}$ = 0; $C_{CBX}$ = 0.1 $\mu$ F	V <sub>VS</sub> +10V		V <sub>VS</sub> +14V	
R <sub>GH1</sub> R <sub>GH2</sub>	Gate discharge resistance	EN = LOW	10	100		kΩ
R <sub>S1</sub> R <sub>S2</sub>	Sink resistance		10	100		kΩ
Drivers f	or external lowside power MOS	·				
R <sub>GL1L</sub> R <sub>GL2L</sub>	ON-resistance of SINK stage	I <sub>GLX</sub> = 50mA; T <sub>J</sub> = 25°C I <sub>GLX</sub> = 50mA; T <sub>J</sub> = 125°C			10 20	Ω Ω
R <sub>GL1H,</sub> R <sub>GL2H</sub>	ON-resistance of SOURCE stage	$I_{GLX}$ = -50mA; T <sub>J</sub> = 25°C $I_{GLX}$ = -50mA; T <sub>J</sub> = 125°C			10 20	Ω Ω
V <sub>GL1H,</sub> V <sub>GL2H</sub>	Gate ON voltage (SOURCE)	$\label{eq:VVS} \begin{array}{ll} V_{VS} = 8V; \ I_{GLX} = 0 & 7V \\ V_{VS} = 13.5V; \ I_{GLX} = 0 & 10V \\ V_{VS} = 20V; \ I_{GLX} = 0 & 10V \end{array}$		V <sub>VS</sub> V <sub>VS</sub> 14V		
R <sub>GL1</sub> R <sub>GL2</sub>	Gate discharge resistance	EN = LOW	10	100		kΩ
2. not teste	d in production: guaranteed by design an	d verified in characterization	•		•	
Timing of	the drivers					

Thining U									
t <sub>GH1LH</sub> t <sub>GH2LH</sub>	Propagation delay time	Fig. 2 $V_{VS}$ = 13.5V $V_{S1}$ = $V_{S2}$ =0 $C_{CBX}$ = 0.1µF RPR= 10kW			500	ns			

## Table 5. Electrical Characteristcs (continued)

(8V < V<sub>VS</sub> < 20V, V<sub>EN</sub> = HIGH, -40°C  $\leq$  T<sub>J</sub>  $\leq$  150°C, unless otherwise specified. The voltages are refered to GND and currents are assumed positive, when current flows into the pin

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Unit
t <sub>GH1LH</sub> t <sub>GH2LH</sub>	Propagation delay time including cross conduction protection time t <sub>CCP</sub>	cross conduction protection time $V_{VS} = 13.5V$ CCP $V_{S1} = V_{S2} = 0$				
t <sub>GH1HL</sub> t <sub>GH2HL</sub>	Propagation delay time	C <sub>CBX</sub> = 0.1µF C <sub>PR</sub> = 150pF; R <sub>PR</sub> = 10kΩ; 5)			500	ns
tgl1lh tgl2lh	Propagation delay time	Fig. 2 $V_{VS} = 13.5V$ $V_{S1} = V_{S2} = 0$ $C_{CBX} = 0.1 \mu F$ $R_{PR} = 10 k \Omega$			500	ns
t <sub>GL1LH</sub> t <sub>GL2LH</sub>	Propagation delay time including cross conduction protection time t <sub>CCP</sub>	Fig. 2 V <sub>VS</sub> = 13.5V V <sub>S1</sub> = V <sub>S2</sub> =0	0.7	1	1.3	μS
t <sub>GL1HL</sub> t <sub>GL2HL</sub>	Propagation delay time	C <sub>CBX</sub> = 0.1μF C <sub>PR</sub> = 150pF; R <sub>PR</sub> = 10kΩ; 5)			500	ns
t <sub>GH1r</sub> t <sub>GH2r</sub>	Rise time	Fig. 2 V <sub>VS</sub> = 13.5V			1	μS
t <sub>GH1f</sub> t <sub>GH2f</sub>	Fall time	V <sub>S1</sub> = V <sub>S2</sub> =0 C <sub>CBX</sub> = 0.1µF			1	μS
t <sub>GL1r</sub> t <sub>GL2r</sub>	Rise time	C <sub>GHX</sub> = 4.7nF C <sub>GLX</sub> = 4.7nF			1	μS
t <sub>GL1f</sub> t <sub>GL2f</sub>	Fall time	R <sub>PR</sub> = 10kΩ;			1	μS
Short Cir	cuit Detection					
V <sub>S1TH</sub> V <sub>S2TH</sub>	Threshold voltage			4		V
t <sub>SCd</sub>	Detection time		5	10	15	μS
Step up c	converter (ST) (5.2V $\leq$ V <sub>VS</sub> < 1	10V)				
V <sub>STH</sub>	ST disable HIGH threshold				10	V
V <sub>STh</sub>	ST disable threshold hysteresis voltage <sup>2)</sup>		1		2	V
R <sub>DSON</sub>	Open drain ON resistance	V <sub>VS</sub> = 5.2V; I <sub>ST</sub> = 50mA			20	Ω
f <sub>ST</sub>	Clock frequency	1	50	100	149	kHz

2. not tested in production: guaranteed by design and verified in characterization

5. tested with differed values in production but guaranteed by design and verified in characterization

Figure 4. Timing of the ISO-interface

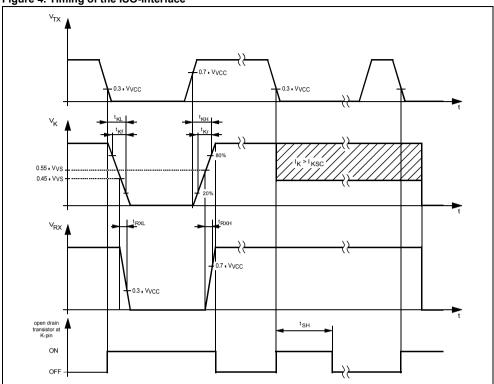
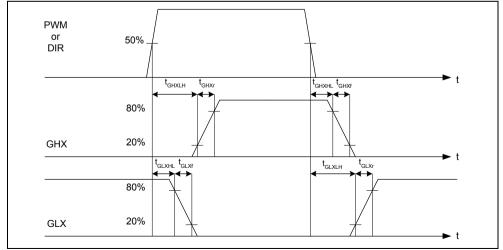
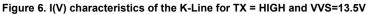
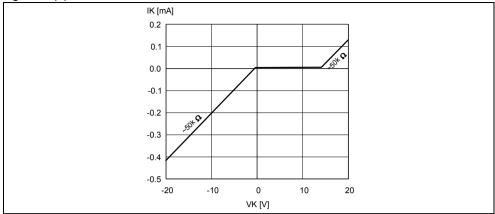
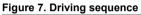


Figure 5. Timing of the drivers for the external MOS regarding the inputs DIR and PWM









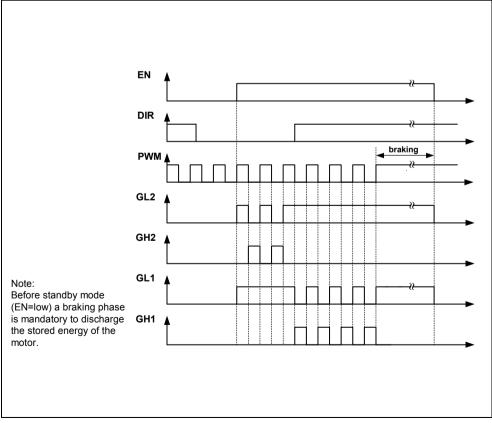


Figure 8. Charging time of an external capacitor of 10nF connected to CP pin at  $\,V_{VS}$  =8V and  $\,V_{VS}$  =13.5V

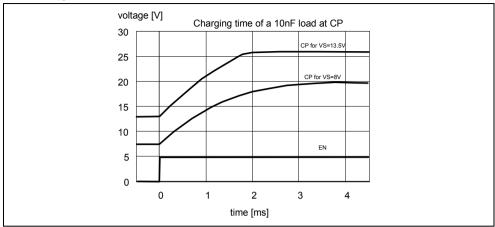
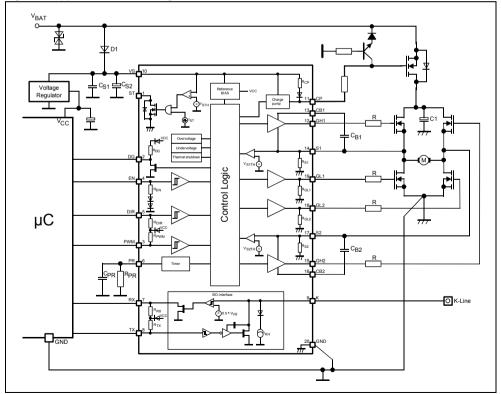


Figure 9. Application Circuit Diagram



# 3 FUNCTIONAL DESCRIPTION

## 3.1 General

The L9904 integrated circuit (IC) is designed to control four external N-channel MOS transistors in H-Bridge configuration for DC-motor driving in automotive applications. It includes an ISO9141 compatible interface. A typical application is shown in fig.9.

# 3.2 Voltage supply

The IC is supplied via an external reverse battery protection diode to the  $V_{VS}$  pin. The typical operating voltage range is down to 8V.

The supply current consumption of the IC composes of static and a dynamic part. The static current is typically 5.8mA. The dynamical current  $I_{dyn}$  is depending of the PWM frequency  $f_{PWM}$  and the required gate charge  $Q_{Gate}$  of the external power mos transistor. The current can be estimated by the expression:

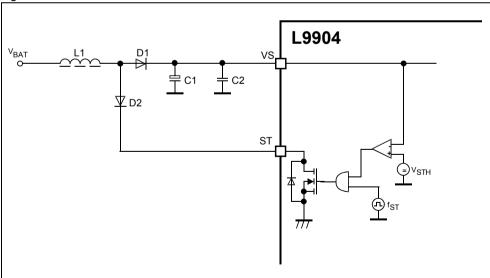
$$I_{dyn} = 2 \cdot f_{PWM} \cdot Q_{Gate}$$

An external power transistor with a gate charge of  $Q_{Gate}$  = 160nC and a PWM frequency of  $f_{PWM}$  = 20kHz requires a dynamical supply current of  $I_{dyn}$  = 6.4mA.

The total supply current consumption is  $I_{VS} = 5.8mA + 6.4mA = 12.2mA$ .

#### 3.3 Extended supply voltage range (ST)

The operating battery voltage range can be extended down to 6V using the additional components shown in fig.7. A small inductor of L~150µH (I<sub>peak</sub>~500mA) in series to the battery supply builts up a step up converter with the switching open drain output ST. The switching frequency is typical 100kHz with a fixed duty cycle of 50%. The step up converter starts below V<sub>VS</sub> < 8V, increases the supply voltage at the V<sub>S</sub> pin and switches off at V<sub>VS</sub> > 10V to avoid EME at nominal battery voltage. The diode D2 in series with the ST pin is necessary only for systems with negative battery voltage. No additional load can be driven by the step up converter.



#### Figure 10.

# 3.4 Control inputs (EN. DIR. PWM)

The cmos level inputs drive the device as shown in fig.7 and described in the truth table.

The device is activated with enable input HIGH signal. For enable input floating (not connected) or VEN=0V the device is in standby mode. When activating the device a wake-up time of 50us is recommended to stabilize the internal supplies.

The DIR and PWM inputs control the driver of the external H-Bridge transistors. The motor direction can be choosen with the DIR input, the duty cycle and frequency with the PWM input. Unconnected inputs are defined by internal pull up resistors. During wake-up and braking and before disactivating the IC via enable both inputs should be driven HIGH.

Status	Con	itrol in	outs	Device status			Drive		for ext r MOS	ternal	Diagnostic	Comment	
	EN	DIR	PWM	TS	OV	UV	SC	GH1	GL1	GH2	GL2	DG	
1	0	х	x	х	х	х	х	R <sup>7)</sup>	R	R <sup>7)</sup>	R	Т	standby mode
2	1	х	x	1	0	0	0	L	L	L	L	L	thermal shutdown
3	1	х	х	0	1	0	0	L	L	L	L	L	overvoltage
4	1	х	х	0	0	1	0	L	L	L	L	L	undervoltage
5	1	х	x	0	0	0	1	X <sup>6)</sup>	X <sup>6)</sup>	X <sup>6)</sup>	X <sub>6</sub>	L	short circuit 6)
6	1	0	0	0	0	0	0	L	Н	Н	L	Н	
7	1	х	1	0	0	0	0	L	Н	L	Н	Н	braking mode
8	1	1	0	0	0	0	0	Н	L	L	Н	Н	
Symbols	s: x C	)on't ca	are		•	R:Re	sistive	output		•		TS:Therma	I shutdown

#### Table 6 Truth table:

47/

0: Logic LOW or not active

1: Logic HIGH or active

L: Output in sink condition

OV:Overvoltage

UV:Undervoltage

H: Output in source condition

T: Tristate SC:Short Circuit

6. Only those external MOS transistors of the H-Bridge which are in short circuit condition are switched off. All others remain driven by DIR and PWM.

7. See Application Note AN2229

# 3.5 Thermal shutdown

When the junction temperature exceeds T<sub>ISD</sub> all driver are switched in sink condition (L), the K- output is off and the diagnostic DG is LOW until the junction temperature drops below TJSD - TJHYST.

# 3.6 Overvoltage Shutdown

When the supply voltage V<sub>VS</sub> exceeds the overvoltage threshold V<sub>VSOVH</sub> all driver are switched in sink condition (L), the K- output is off and the diagnostic DG is LOW.

# 3.7 Undervoltage Shutdown

For supply voltages below the undervoltage disable threshold the gate driver remains in sink condition (L) and the diagnostic DG is low.

# 3.8 Short Circuit Detection

The output voltage at the S1 and S2 pin of the H-Bridge is monitored by comparators to detect shorts to ground or battery. The activated external highside MOS transistor will be switched off if the voltage drop remains below the comparator threshold voltage  $V_{S1TH}$  and  $V_{S2TH}$  for longer than the short current detection time  $t_{SCd}$ . The transistor remains in off condition, the diagnostic output goes LOW until the DIR or PWM input status will be changed. The status doesn't change for the other MOS transistors. The external lowside MOS transistor will be switched off if the voltage drop passes over the comparator threshold voltage  $V_{S1TH}$  and  $V_{S2TH}$  for longer than the short current detection time  $t_{SCd}$ . The transistor remains in off condition, the diagnostic output goes LOW until the DIR or PWM input status will be switched off if the voltage drop passes over the comparator threshold voltage  $V_{S1TH}$  and  $V_{S2TH}$  for longer than the short current detection time  $t_{SCd}$ . The transistor remains in off condition, the diagnostic output goes LOW until the DIR or PWM input status will be changed. The status doesn't change for the other MOS transistors.

## 3.9 Diagnostic Output (DG)

The diagnostic output provides a real time error detection, if monitors the following error stacks: Thermal shutdown, overvoltage shutdown, undervoltage shutdown and short circuit shutdown. The open drain output with internal pull up resistor is LOW if an error is occuring.

#### 3.10 Bootstrap capacitor (CB1,CB2)

To ensure, that the external power MOS transistors reach the required  $R_{DSON}$ , a minimum gate source voltage of 5V for logic level and 10V for standard power MOS transistors has to be guaranteed. The highside transistors require a gate voltage higher than the supply voltage. This is achieved with the internal chargepump circuit in combination with the bootstrap capacitor. The bootstrap capacitor is charged, when the highside MOS transistor is OFF and the lowside is ON. When the lowside is switched OFF, the charged bootstrap capacitor is able to supply the gate driver of the highside power MOS transistor. For effective charging the values of the bootstrap capacitors should be larger than the gate-source capacitance of the power MOS and respect the required PWM ratio.

#### 3.11 Chargepump circuit (CP)

The reverse battery protection can be obtained with an external N-channel MOS transistor as shown in fig.6. In this case its drain-bulk diode provides the protection. The output CP is intended to drive the gate of this transistor above the battery voltage to switch on the MOS and to bypass the drain-bulk diode with the  $R_{DSON}$ . The CP has a connection to VS through an internal diode and a 20k $\Omega$  resistor.

#### 3.12 Gate drivers for the external N-channel power MOS transistors (GH1, GH2, GL1, GL2)

High level at EN activates the driver of the external MOS under control of the DIR and PWM inputs (see truth table and driving sequence fig.4). The external power MOS gates are connected via series resistors to the device to reduce electro magnetic emission (EME) of the system. The resistors influence the switching behaviour. They have to be choosen carefully. Too large resistors enlarge the charging and discharging time of the power MOS gate and can generate cross current in the halfbridges. The driver assures a longer switching delay time from source to sink stage in order to prevent the cross conduction.

The gate source voltage is limited to 14V. The charge/discharge current is limited by the R<sub>DSON</sub> of the driver. The drivers are not protected against shorts.

#### 3.13 Programmable cross conduction protection

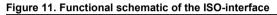
The external power MOS transistors in H-Bridge ( two half bridges) configuration are switched on with an additional delay time  $t_{CCP}$  to prevent cross conduction in the halfbridge. The cross conduction protection time  $t_{CCP}$  is determined by the external capacitor  $C_{PR}$  and resistor  $R_{PR}$  at the PR pin. The capacitor  $C_{PR}$  is charged up to the voltage limit  $V_{PRH}$ . A level change on the control inputs DIR and PWM switches off the concerned external MOS transistor and the charging source at the PR pin. The resistor  $R_{PR}$  discharges the capacitor  $C_{PR}$ . The concerned external power MOS transistor will be switched on again when the voltage at PR reaches the value of  $V_{PRL}$ . After that the CPR will be charged again. The capacitor  $C_{PR}$  should be choosen between 100pF and 1nF. The resistor  $R_{PR}$  should be higher than 7kW. The delay time can be expressed as follows:

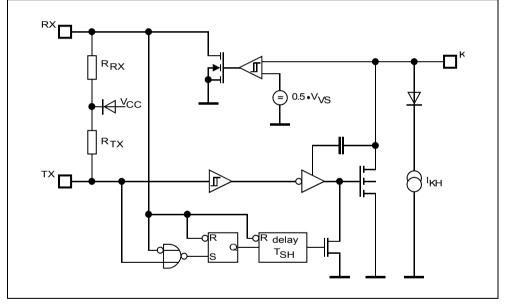
 $t_{CCP} = R_{PR} \cdot C_{PR} \cdot \ln N_{PR}$  with  $N_{PR} = V_{PRH} / V_{PRL} = 2$ 

 $t_{CCP}$ = 0.69 ·  $R_{PR}$  ·  $C_{PR}$ 

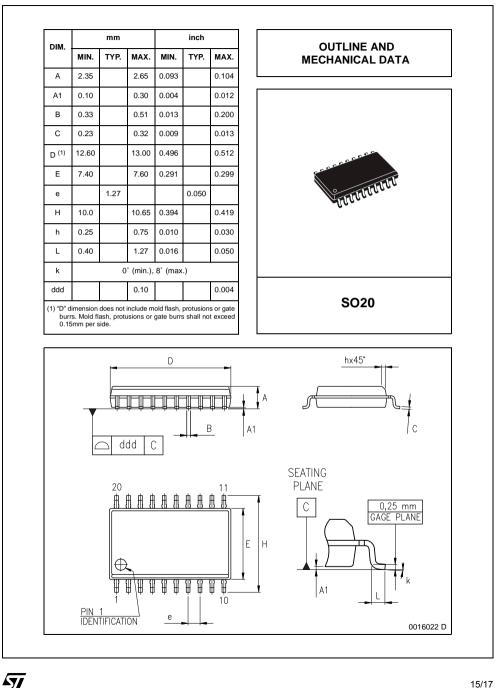
#### 3.14 ISO-Interface

The ISO-Interface provides the communication between the micro controller and a serial bus with a baud rate up to 60kbit/s via a single wire which is  $V_{BAT}$  and GND compatible. The logic level transmission input TX drives the open drain K-output. The K output can be connected to a serial bus with a pull up resistor to  $V_{BAT}$ . The K-pin is protected against overvoltage, short to GND and VS and can be driven beyond  $V_{VS}$  and GND. During lack of  $V_{VS}$  or GND the output shows high impedance characteristic. The open drain output RX with an internal pull up resistor monitors the status at the K-pin to read the received data and control the transmitted data. Short circuit condition at K-pin is recognized if the internal open drain transistor isn't able to pull the voltage potential at K-pin below the threshold of  $0.45 \cdot V_{VS}$ . Then the RX stays in high condition. A timer starts and switches the open drain transistor after typ. 20µs off. A next low at the TX input resets the timer and the open drain transistor switches on again.









15/17

# Table 7. Revision History

Date	Revision	Description of Changes
October 2002	1	First Issue on ST-Press DMS
January 2004	2	Migration from ST-Press to EDOCS DMS
May 2004	3	Change Maturity from Product Preview to Final.
October 2005	4	Inserted on pag 12 AN2229 ref.
September 2013	5	Updated disclaimer.

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